

Notice of References Cited	Application/Control No. 10/646,261		Applicant(s)/Patent Under Reexamination LIEBENOW, FRANK	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-20040021777A1	02-2004	Ishiyama et al.	348/211.2
*	B	US-20040212692A1	10-2004	Nakami et al.	348/224.1
*	C	US-6005613	12-1999	Endlsey et al.	348/231.6
*	D	US-6903762B2	06-2005	Prabhu et al.	348/207.1
*	E	US-20040027473A1	02-2004	Suzuki, Yuji	348/333.02
*	F	US-7136103B2	11-2006	Oeda et al.	348/333.02
*	G	US-20020030754A1	03-2002	Sugimoto, Masahiko	348/333.02
*	H	US-20050018766A1	01-2005	Iwamura, Ryuichi	375/240.01
*	I	US-20010048472A1	12-2001	Inoue et al.	348/207
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002152570 A	05-2002	Japan	Tanaka, Hiroshi	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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